Application/Control No. Applicant(s)/Patent Under Reexamination 10/710,581 HWANG ET AL. **Notice of References Cited** Art Unit Examiner Page 1 of 1 Tuan H. Nguyen 2813 **U.S. PATENT DOCUMENTS Document Number** Date Name Classification Country Code-Number-Kind Code MM-YYYY * Rotondaro et al. 07-2005 438/287 US-6,919,251 * 04-2005 US-2005/0081781 Lin et al. 117/104 * 06-2005 US-2005/0118353 Chen et al. 427/569 * 07-2005 Chen et al. 438/706 US-2005/0164511 D E US-US-US-G US-Н US-US-US-K US-

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